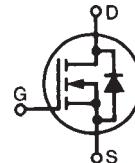


PolarHT™ Power MOSFET

N-Channel Enhancement Mode
Avalanche Rated

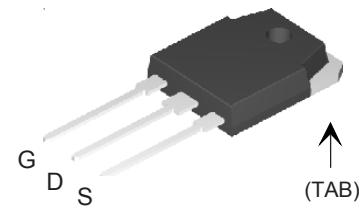
IXTQ 200N06P

V_{DSS} = 60 V
I_{D25} = 200 A
R_{DS(on)} ≤ 6.0 mΩ



Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	T _J = 25°C to 175°C	60		V
V_{DGR}	T _J = 25°C to 175°C; R _{GS} = 1 MΩ	60		V
V_{GS}	Transient	±30		V
V_{GSM}	Continuous	±20		V
I_{D25}	T _C = 25°C	200		A
I_{D(RMS)}	External lead current limit	75		A
I_{DM}	T _C = 25°C, pulse width limited by T _{JM}	400		A
I_{AR}	T _C = 25°C	60		A
E_{AR}	T _C = 25°C	80		mJ
E_{AS}	T _C = 25°C	4.0		J
dv/dt	I _S ≤ I _{DM} , di/dt ≤ 100 A/μs, V _{DD} ≤ V _{DSS} , T _J ≤ 150°C, R _G = 4 Ω	10		V/ns
P_D	T _C = 25°C	714		W
T_J		-55 ... +175		°C
T_{JM}		175		°C
T_{stg}		-55 ... +150		°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300		°C
T_{SOLD}	Plastic body for 10 s	260		°C
M_d	Mounting torque (TO-3P)	1.13/10		Nm/lb.in.
Weight	TO-3P	5.5		g

TO-3P (IXTQ)



G = Gate
S = Source

D = Drain
TAB = Drain

Features

- International standard package
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect

Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions (T _J = 25°C, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	V _{GS} = 0 V, I _D = 250 μA	60		V
V_{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	2.5		V
I_{GSS}	V _{GS} = ±20 V _{DC} , V _{DS} = 0		±100	nA
I_{DSS}	V _{DS} = V _{DSS} V _{GS} = 0 V	T _J = 150°C	25	μA
			250	μA
R_{DS(on)}	V _{GS} = 10 V, I _D = 60 A V _{GS} = 15 V, I _D = 400 A Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %	5.0	6.0	mΩ

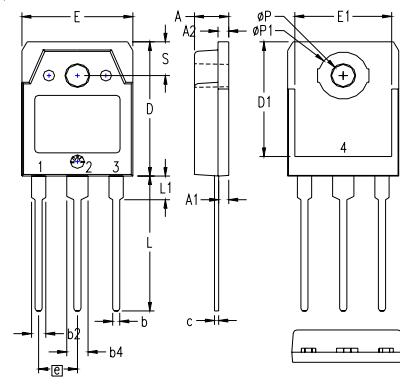
Symbol	Test Conditions	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 60 \text{ A}$, pulse test	45	65	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	5400	pF	
		3550	pF	
		1360	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 60 \text{ A}$ $R_G = 3.3 \Omega$ (External)	35	ns	
		60	ns	
		90	ns	
		40	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$	200	nC	
		37	nC	
		110	nC	
R_{thJC}			0.21	$^{\circ}\text{C}/\text{W}$
R_{thCS}		0.21		$^{\circ}\text{C}/\text{W}$

Source-Drain Diode

Characteristic Values
($T_J = 25^{\circ}\text{C}$, unless otherwise specified)

Symbol	Test Conditions	Min.	Typ.	Max.
I_s	$V_{GS} = 0 \text{ V}$		200	A
I_{SM}	Repetitive		400	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM}	$I_F = 25 \text{ A}, -di/dt = 100 \text{ A}/\mu\text{s}$ $V_R = 30 \text{ V}, V_{GS} = 0 \text{ V}$	90	ns	
		1.0	μC	

TO-3P (IXTQ) Outline

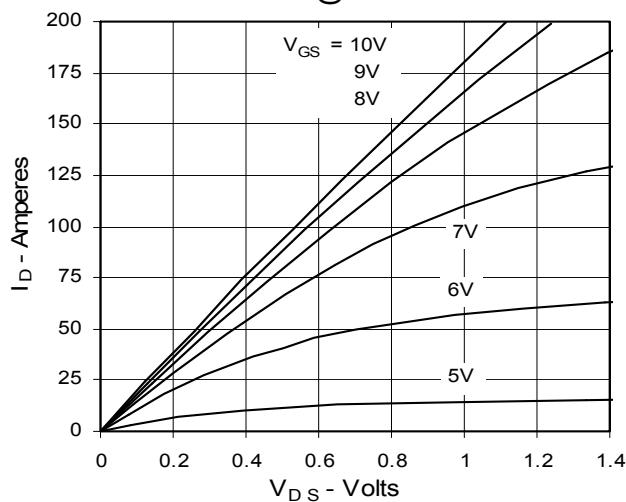


1 - GATE
2 - DRAIN (COLLECTOR)
3 - SOURCE (EMITTER)
4 - DRAIN (COLLECTOR)

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.193	4.70	4.90
A1	.051	.059	1.30	1.50
A2	.057	.065	1.45	1.65
b	.035	.045	0.90	1.15
b2	.075	.087	1.90	2.20
b4	.114	.126	2.90	3.20
c	.022	.031	0.55	0.80
D	.780	.791	19.80	20.10
D1	.665	.677	16.90	17.20
E	.610	.622	15.50	15.80
E1	.531	.539	13.50	13.70
e	.215 BSC		5.45 BSC	
L	.779	.795	19.80	20.20
L1	.134	.142	3.40	3.60
ϕP	.126	.134	3.20	3.40
$\phi P1$.272	.280	6.90	7.10
S	.193	.201	4.90	5.10

All metal areas are tin plated.

**Fig. 1. Output Characteristics
@ 25°C**



**Fig. 3. Output Characteristics
@ 150°C**

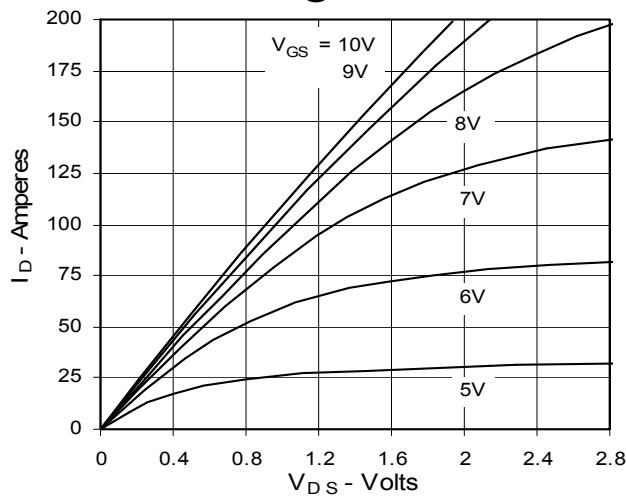
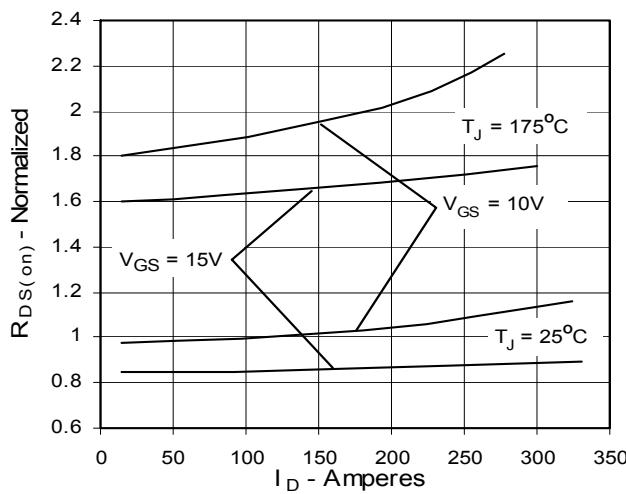


Fig. 5. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Drain Current



**Fig. 2. Extended Output Characteristics
@ 25°C**

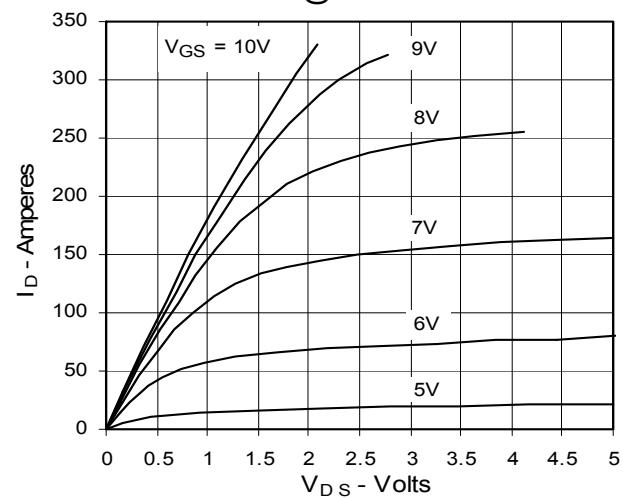


Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Junction Temperature

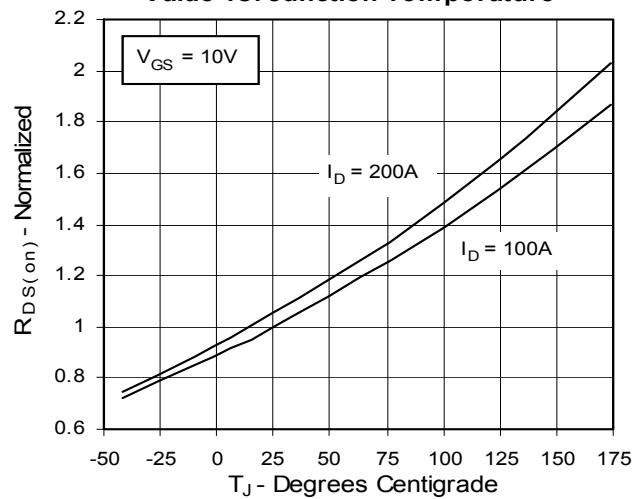


Fig. 6. Drain Current vs. Case Temperature

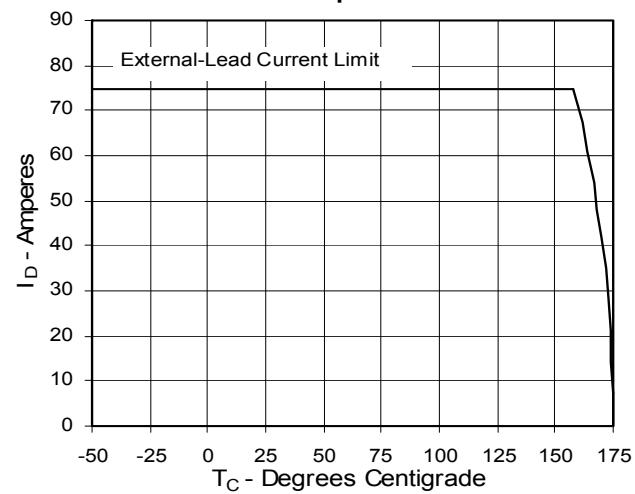


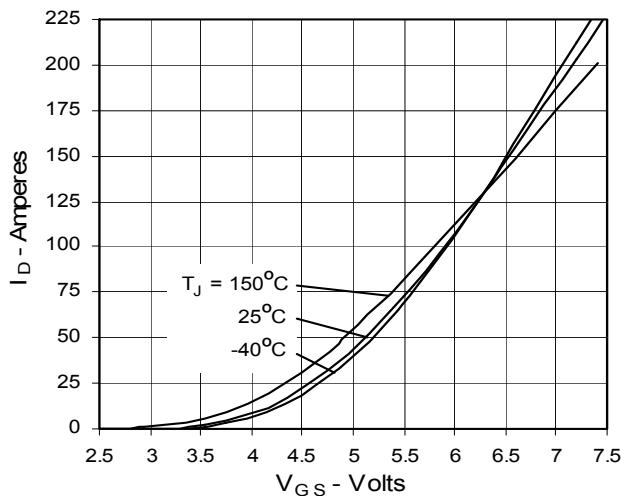
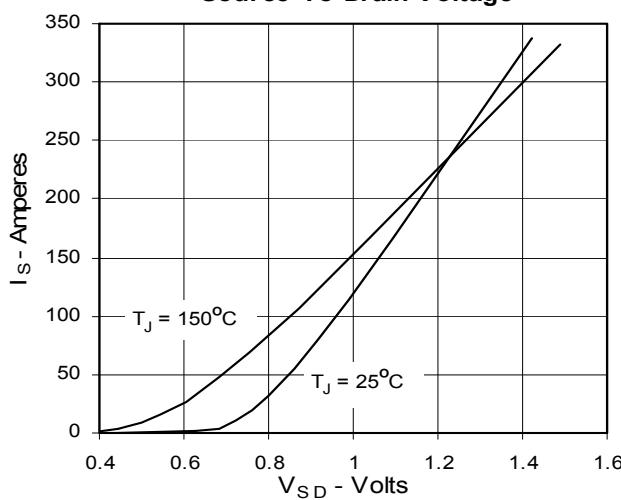
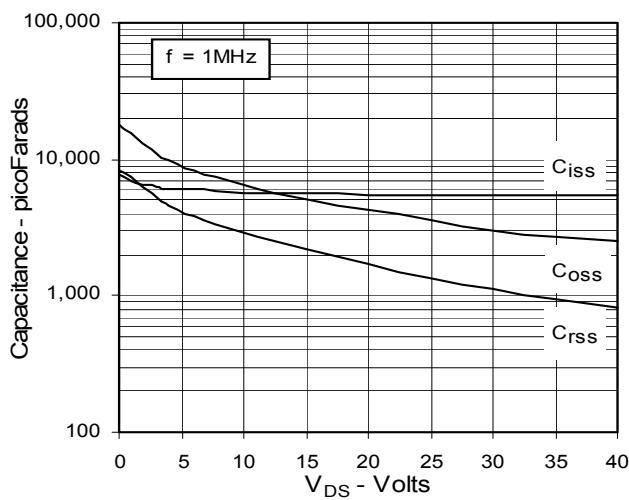
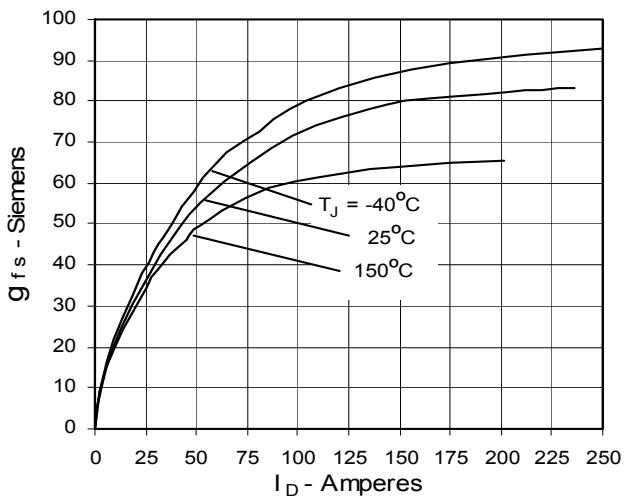
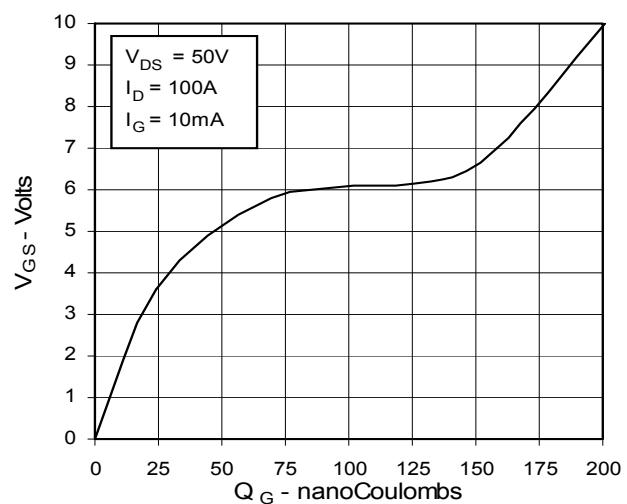
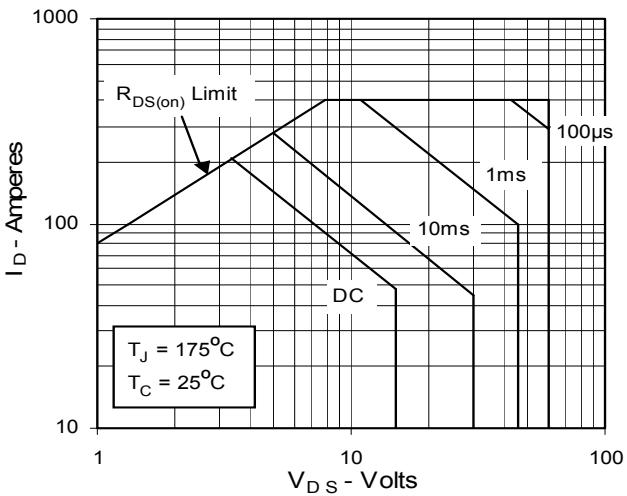
Fig. 7. Input Admittance**Fig. 9. Source Current vs. Source-To-Drain Voltage****Fig. 11. Capacitance****Fig. 8. Transconductance****Fig. 10. Gate Charge****Fig. 12. Forward-Bias Safe Operating Area**

Fig. 13. Maximum Transient Thermal Resistance